

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. APPM/6877/CMP/ CMP/RKK	Serial No. 10/611,805
LISTS OF PATENTS AND PUBLICATIONS CITED BY APPLICANT (Use several sheets if necessary)		Applicant Sun, et al.	Confirmation No. UNKNOWN
Examiner UNKNOWN		Filing Date June 30, 2003	Group 1742 UNKNOWN

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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
NSB	A1	2002/0077037	06/20/2002	Tietz	451	41	07/20/2001
	A2	2002/0070126	06/13/2002	Sato	205	640	09/19/2001
	A3	2002/0008036	01/24/2002	Wang	205	118	04/18/2001
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	A5	2001/0040100	11/15/2001	Wang	205	220	04/16/2001
	A6	2001/0036746	11/01/2001	Sato et al.	438	745	03/08/2001
	A7	2001/0024878	09/27/2001	Nakamura	438	691	03/26/2001
	A8	6,440,295	08/27/2002	Wang	205	640	02/04/2000
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	B2	2001-77117	03-23-2001	JAPAN	H 01 L	21/3205		X
	B3	JP 11042554	02-16-1999	JAPAN	B24B	37/04		X
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	C1	Nogami, "An Innovation in Integrate Porous Low-K Materials and Copper." InterConnect Japan 2001; Honeywell Seminar December 6, 2001, p 1-12.

Examiner *W. Butler* Date Considered *8-7-5-05*

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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	A14	6,273,798	08/14/2001	Berman	451	72	07/27/1999
	A15	6,248,222	06/19/2001	Wang	204	297.09	09/07/1999
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<u>e</u>	B8	WO 00/59682	10-12-2000	WIPO	B24B	37/04		X
<u>e</u>	B9	WO 00/33356	06-08-2000	WIPO	H01L	---		X
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	C2	U.S. Patent Application 10/151,538 filed on May 16, 2002.
Examiner	<u>NSB</u>	Date Considered <u>7-5-05</u>

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	B12	WO 99/53119	10-21-1999	WIPO	C23C	18/18		X
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	C5	International Search Report for PCT/US 02/11009 dated February 6, 2003.
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	C7	
	C8	

Examiner Ant B... Date Considered July 5, 2005

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Examiner UNKNOWN					Filing Date June 30, 2003		Group 1742 UNKNOWN	

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